OptiMOS®2 Power-Transistor

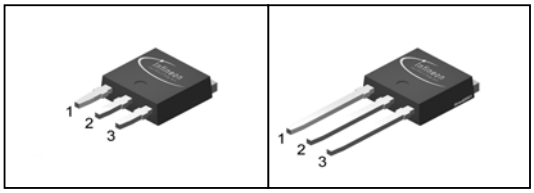
Features

- Ideal for high-frequency dc/dc converters
- Qualified according to JEDEC[1] for target applications
- N-channel - Logic level
- Excellent gate charge x $R_{DS(on)}$ product (FOM)
- Very low on-resistance $R_{DS(on)}$
- Superior thermal resistance
- 175 °C operating temperature
- dv/dt rated
- Pb-free lead plating; RoHS compliant

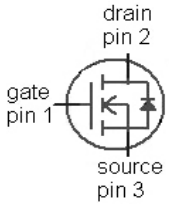
Product Summary

V_{DS}	30	V
$R_{DS(on),max}$	5.8	mΩ
I_D	50	A

PG-TO251-3-11 PG-TO251-3



Type	Package	Marking
IPU06N03LB	PG-TO251-3	06N03LB
IPS06N03LB	PG-TO251-3-11	06N03LB



Maximum ratings, at T_j=25 °C, unless otherwise specified

Parameter	Symbol	Conditions	Value	Unit
Continuous drain current	I_D	T_C=25 °C[2]	50	A
		T_C=100 °C	50	
Pulsed drain current	$I_{D,pulse}$	T_C=25 °C[3]	200	
Avalanche energy, single pulse	E_{AS}	I_D=50 A, R_{GS}=25 Ω	210	mJ
Reverse diode dv/dt	dv/dt	I_D=50 A, V_{DS}=20 V, di/dt=200 A/µs, $T_{j,max}$=175 °C	6	kV/µs
Gate source voltage[4]	V_{GS}		±20	V
Power dissipation	P_{tot}	T_C=25 °C	94	W
Operating and storage temperature	T_j, T_{stg}		-55 ... 175	°C
IEC climatic category; DIN IEC 68-1			55/175/56	

[1] J-STD20 and JESD22

Parameter	Symbol	Conditions	Values			Unit
			min.	typ.	max.	
Thermal characteristics						
Thermal resistance, junction - case	R_{thJC}		-	-	1.6	K/W
SMD version, device on PCB	R_{thJA}	minimal footprint	-	-	62	
		6 cm^2 cooling area[5)]	-	-	40	
Electrical characteristics, at T_j=25 °C, unless otherwise specified						
Static characteristics						
Drain-source breakdown voltage	$V_{(BR)DSS}$	V_{GS}=0 V, I_D=1 mA	30	-	-	V
Gate threshold voltage	$V_{GS(th)}$	V_{DS}=V_{GS}, I_D=40 µA	1.2	1.6	2	
Zero gate voltage drain current	I_{DSS}	V_{DS}=30 V, V_{GS}=0 V, T_j=25 °C	-	0.1	1	µA
		V_{DS}=30 V, V_{GS}=0 V, T_j=125 °C	-	10	100	
Gate-source leakage current	I_{GSS}	V_{GS}=20 V, V_{DS}=0 V	-	10	100	nA
	$R_{DS(on)}$	V_{GS}=4.5 V, I_D=50 A	-	7.3	9.1	mΩ
		V_{GS}=10 V, I_D=50 A	-	4.9	5.8	
Gate resistance	R_G		-	1.2	-	Ω
Transconductance	g_{fs}	$\|V_{DS}\|>2\|I_D\|R_{DS(on)max}$, I_D=50 A	41	83	-	S

[2)] Current is limited by bondwire; with an R_{thJC}=1.6 K/W the chip is able to carry 95 A.

[3)] See figure 3

[4)] $T_{j,max}$=150 °C and duty cycle D <0.25 for V_{GS}<-5 V

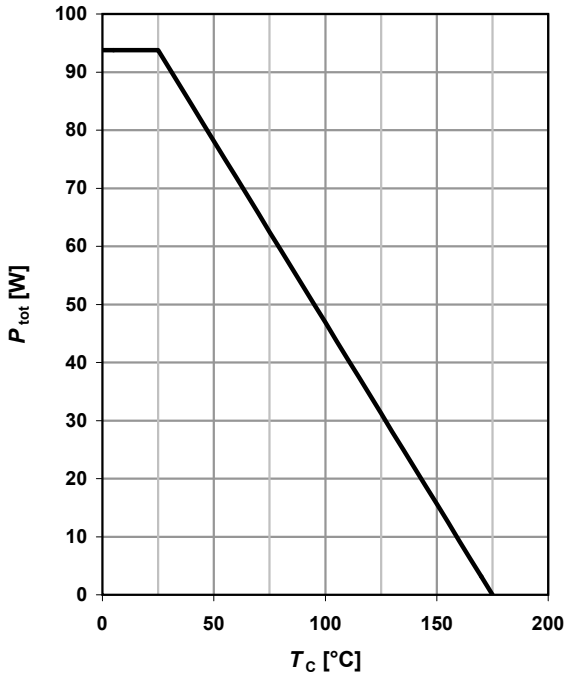
[5)] Device on 40 mm x 40 mm x 1.5 mm epoxy PCB FR4 with 6 cm^2 (one layer, 70 µm thick) copper area for drain connection. PCB is vertical in still air.

Parameter	Symbol	Conditions	Values			Unit
			min.	typ.	max.	
Dynamic characteristics						
Input capacitance	C_{iss}	V_{GS}=0 V, V_{DS}=15 V, f=1 MHz	-	2400	3200	pF
Output capacitance	C_{oss}		-	860	1150	
Reverse transfer capacitance	C_{rss}		-	110	170	
Turn-on delay time	$t_{d(on)}$	V_{DD}=15 V, V_{GS}=10 V, I_D=25 A, R_G=2.7 Ω	-	7	10	ns
Rise time	t_r		-	6	9	
Turn-off delay time	$t_{d(off)}$		-	27	40	
Fall time	t_f		-	4.2	6.3	
Gate Charge Characteristics[6)]						
Gate to source charge	Q_{gs}	V_{DD}=15 V, I_D=25 A, V_{GS}=0 to 5 V	-	7.4	9.9	nC
Gate charge at threshold	$Q_{g(th)}$		-	3.9	5.1	
Gate to drain charge	Q_{gd}		-	4.9	7.3	
Switching charge	Q_{sw}		-	8.4	12	
Gate charge total	Q_g		-	19	25	
Gate plateau voltage	$V_{plateau}$		-	3.1	-	V
Gate charge total, sync. FET	$Q_{g(sync)}$	V_{DS}=0.1 V, V_{GS}=0 to 5 V	-	16	22	nC
Output charge	Q_{oss}	V_{DD}=15 V, V_{GS}=0 V	-	19	26	
Reverse Diode						
Diode continous forward current	I_S	T_C=25 °C	-	-	50	A
Diode pulse current	$I_{S,pulse}$		-	-	200	
Diode forward voltage	V_{SD}	V_{GS}=0 V, I_F=50 A, T_j=25 °C	-	0.92	1.2	V
Reverse recovery charge	Q_{rr}	V_R=15 V, I_F=I_S, di_F/dt=400 A/µs	-	-	10	nC

[6)] See figure 16 for gate charge parameter definition

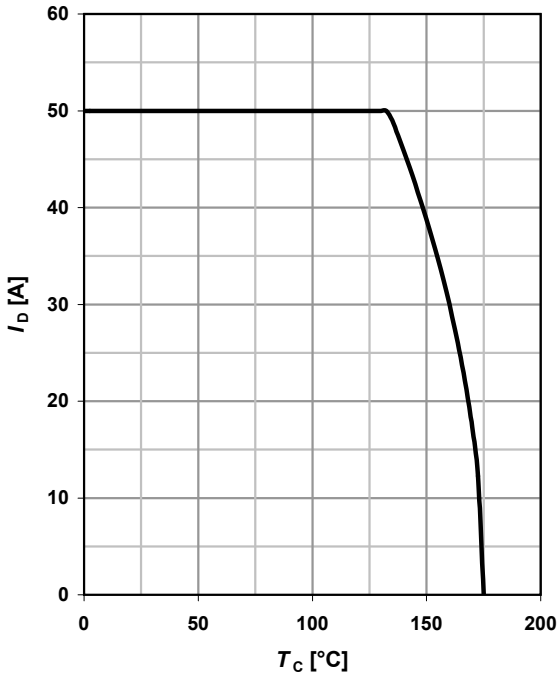
1 Power dissipation

$P_{tot}=f(T_C)$



2 Drain current

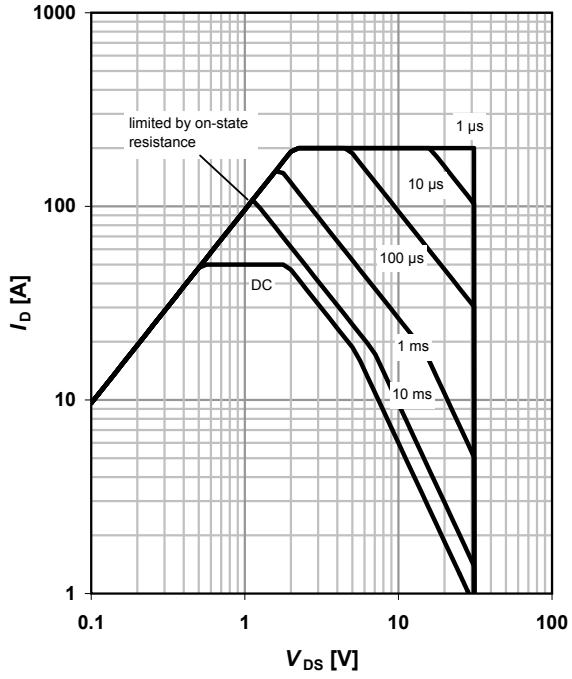
$I_D=f(T_C)$; $V_{GS}\geq 10$ V



3 Safe operating area

$I_D=f(V_{DS})$; $T_C=25$ °C; $D=0$

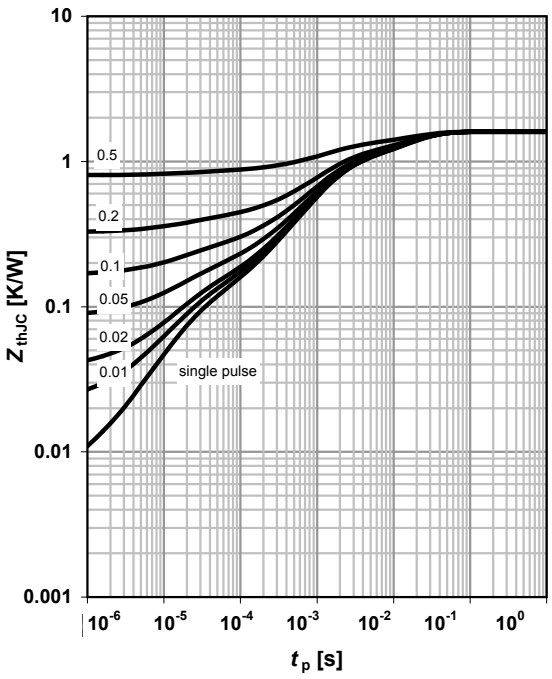
parameter: t_p



4 Max. transient thermal impedance

$Z_{thJC}=f(t_p)$

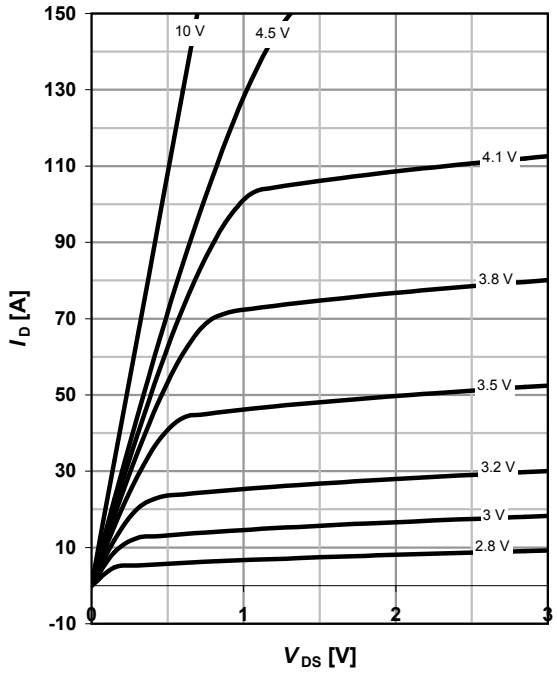
parameter: $D=t_p/T$



5 Typ. output characteristics

I_D=f(V_{DS}); T_j=25 °C

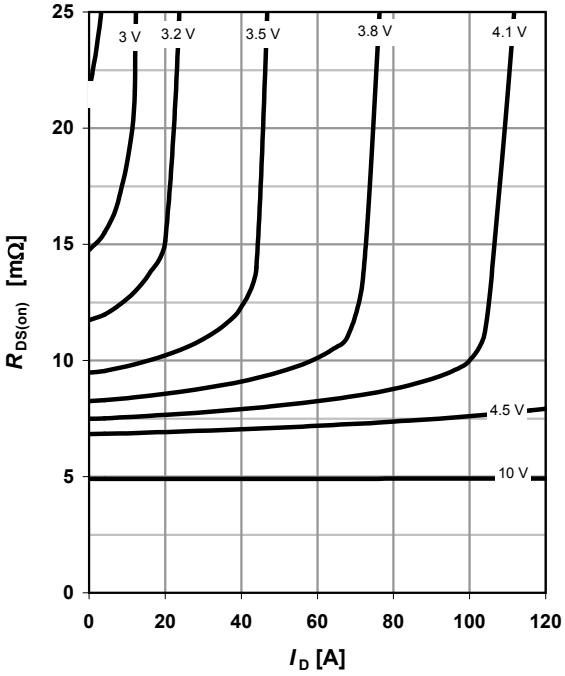
parameter: V_{GS}



6 Typ. drain-source on resistance

$R_{DS(on)}$=f(I_D); T_j=25 °C

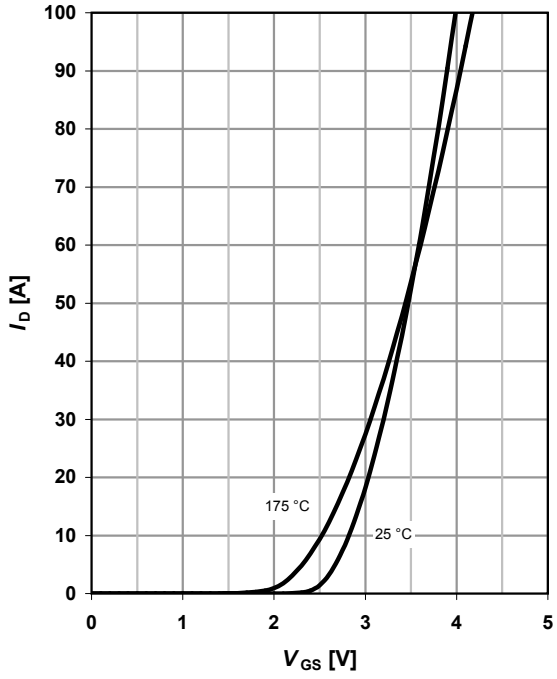
parameter: V_{GS}



7 Typ. transfer characteristics

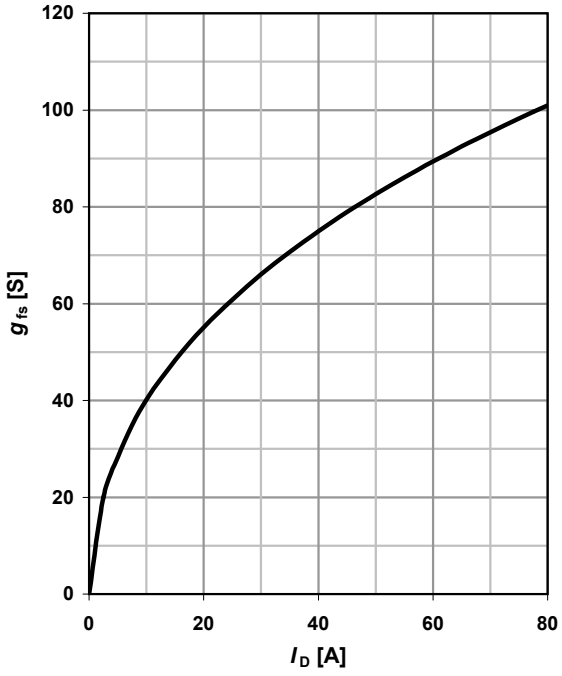
I_D=f(V_{GS}); $|V_{DS}|>2|I_D|R_{DS(on)max}$

parameter: T_j



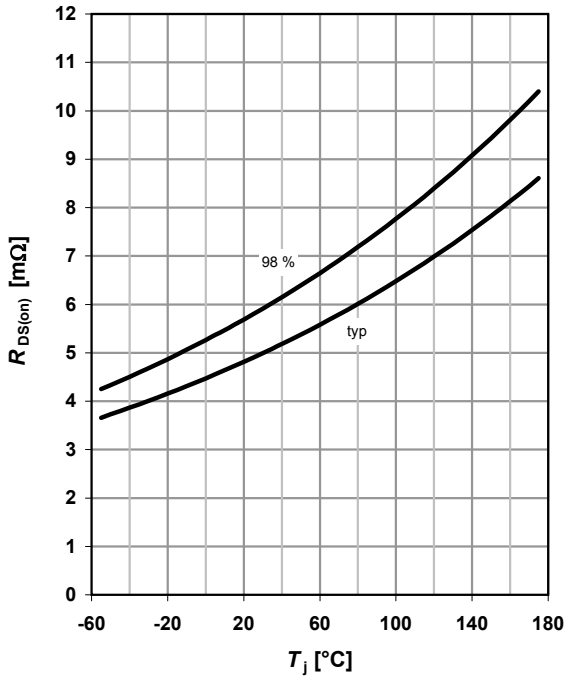
8 Typ. forward transconductance

g_{fs}=f(I_D); T_j=25 °C



9 Drain-source on-state resistance

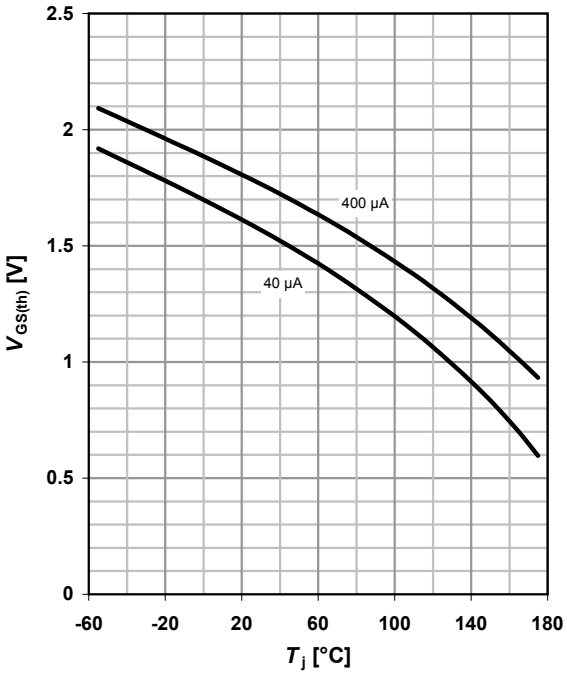
$R_{DS(on)}$=f(T_j); I_D=50 A; V_{GS}=10 V



10 Typ. gate threshold voltage

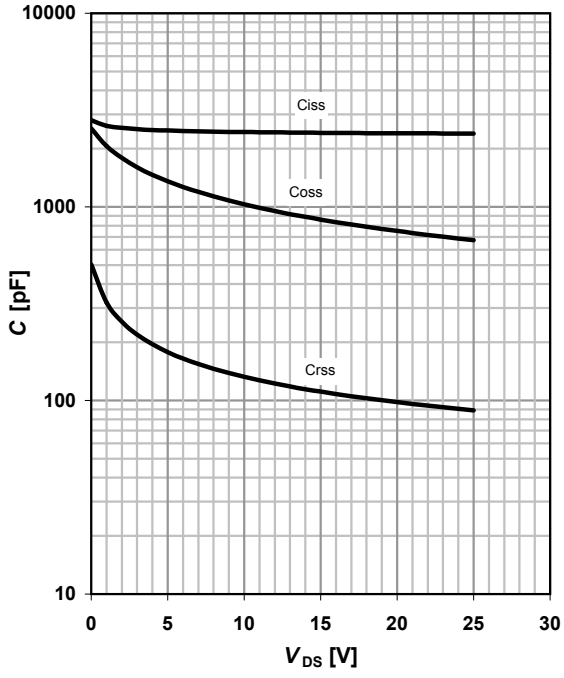
$V_{GS(th)}$=f(T_j); V_{GS}=V_{DS}

parameter: I_D



11 Typ. Capacitances

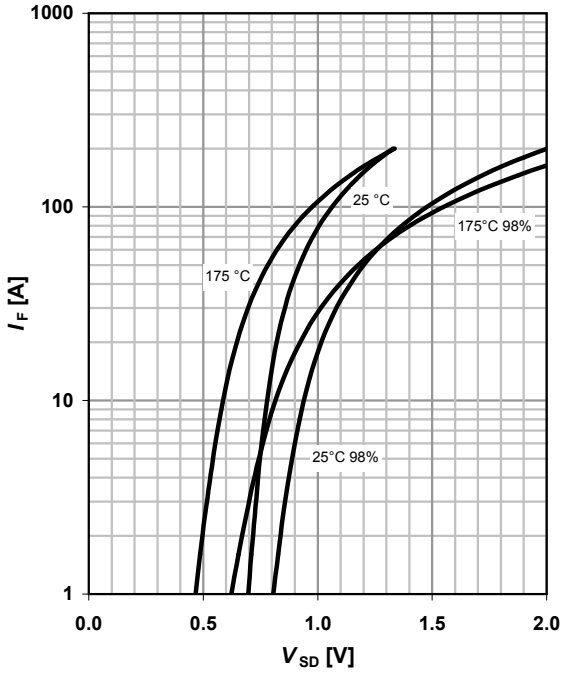
C=f(V_{DS}); V_{GS}=0 V; f=1 MHz



12 Forward characteristics of reverse diode

I_F=f(V_{SD})

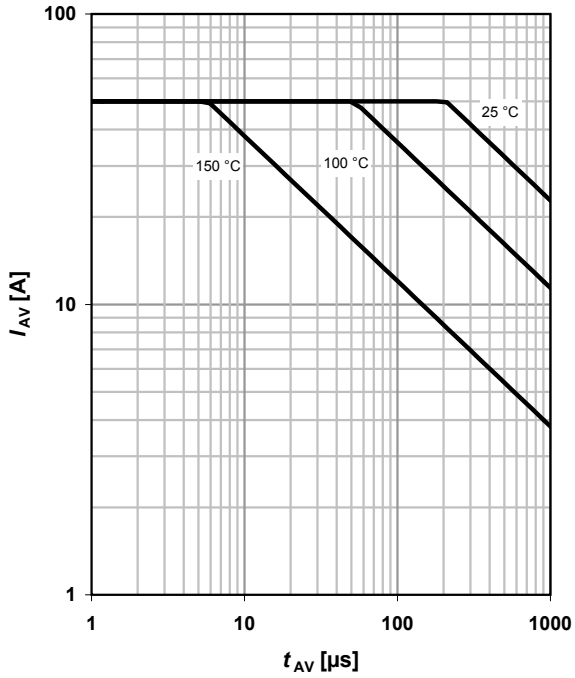
parameter: T_j



13 Avalanche characteristics

I_{AS}=f(t_{AV}); R_{GS}=25 Ω

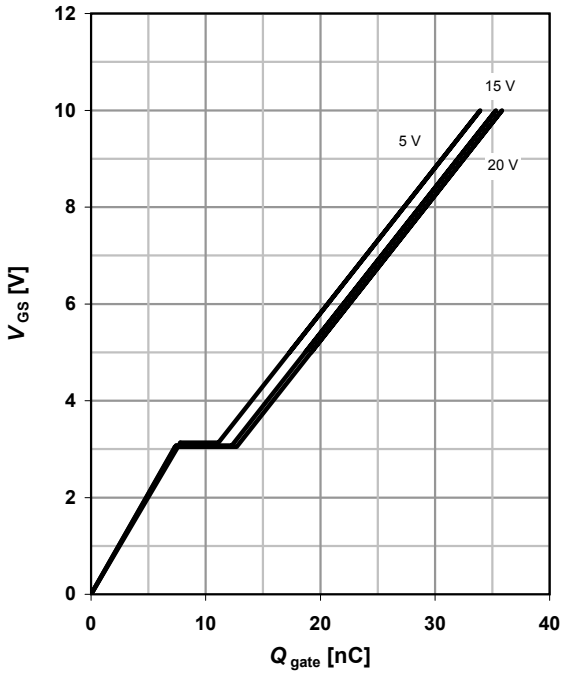
parameter: $T_{j(start)}$



14 Typ. gate charge

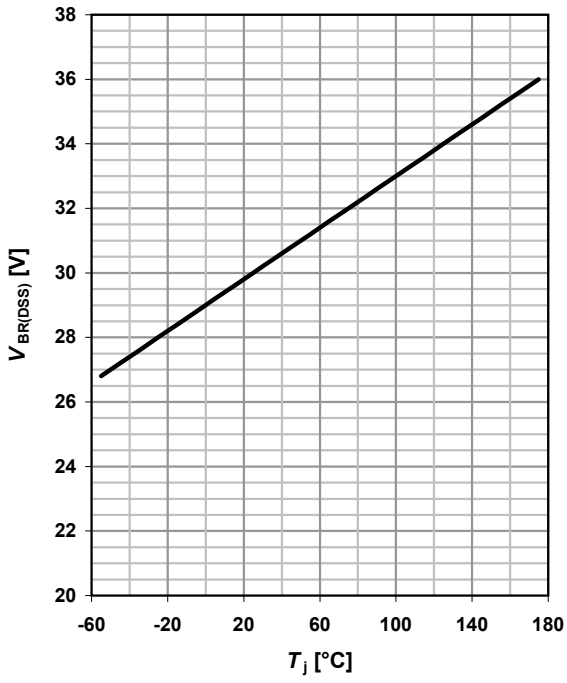
V_{GS}=f(Q_{gate}); I_D=25 A pulsed

parameter: V_{DD}

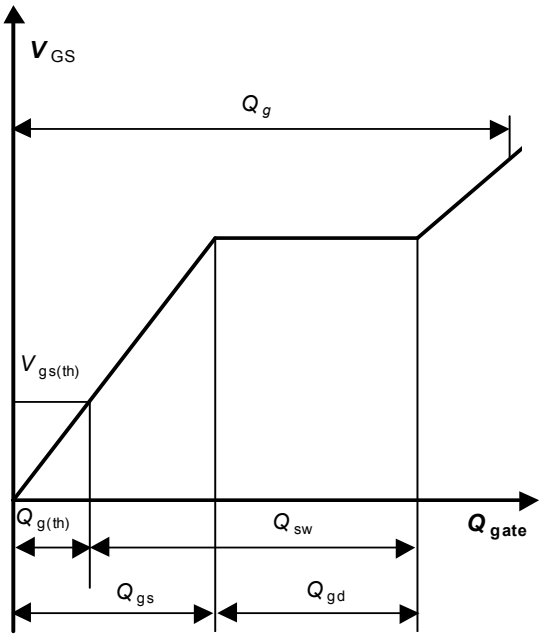


15 Drain-source breakdown voltage

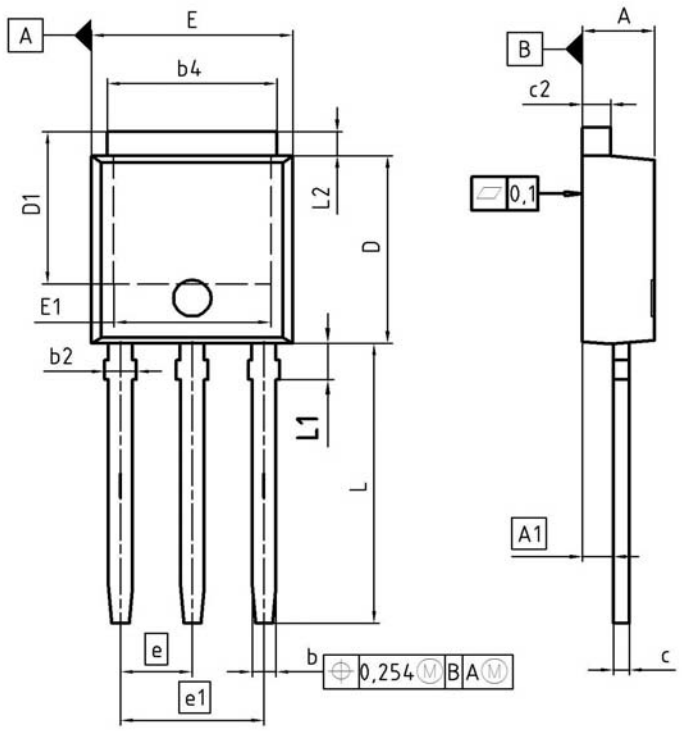
$V_{BR(DSS)}$=f(T_j); I_D=1 mA



16 Gate charge waveforms



PG-TO251-3: Outline



DIM	MILLIMETERS		INCHES	
	MIN	MAX	MIN	MAX
A	2.16	2.41	0.085	0.095
A1	0.90	1.14	0.035	0.045
b	0.64	0.89	0.025	0.035
b2	0.65	1.15	0.026	0.045
b4	4.95	5.50	0.195	0.217
c	0.46	0.60	0.018	0.024
c2	0.46	0.89	0.018	0.035
D	5.97	6.22	0.235	0.245
D1	5.04	5.77	0.198	0.227
E	6.35	6.73	0.250	0.265
E1	4.70	5.21	0.185	0.205
e	2.29		0.090	
e1	4.57		0.180	
N	3		3	
L	8.89	9.65	0.350	0.380
L1	1.90	2.29	0.075	0.090
L2	0.89	1.37	0.035	0.054

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SCALE 0 2.0 0 2.0 4mm

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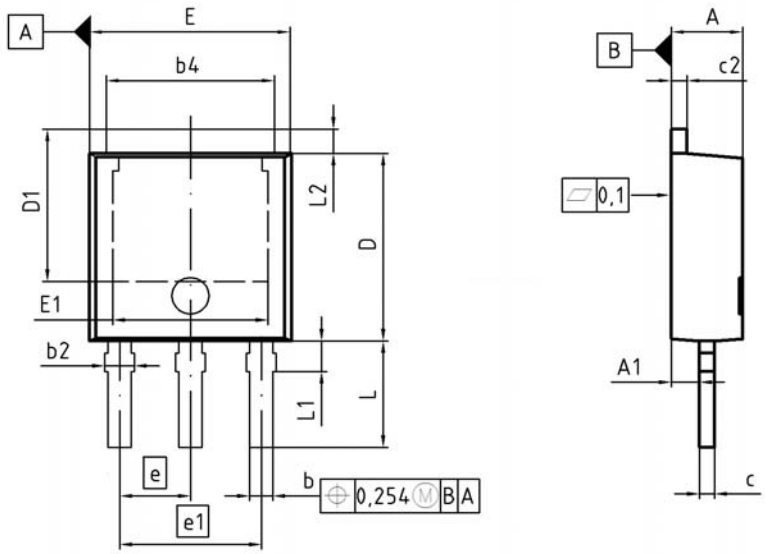
PG-TO251-3-11: Outline



DIM	MILLIMETERS		INCHES	
	MIN	MAX	MIN	MAX
A	2.18	2.39	0.086	0.094
A1	0.80	1.14	0.031	0.045
b	0.64	0.89	0.025	0.035
b2	0.65	1.15	0.026	0.045
b4	4.95	5.50	0.195	0.217
c	0.46	0.58	0.018	0.023
c2	0.46	0.89	0.018	0.035
D	5.97	6.22	0.235	0.245
D1	5.04	5.44	0.198	0.214
E	6.35	6.73	0.250	0.265
E1	4.90	5.10	0.193	0.201
e	2.29		0.090	
e1	4.57		0.180	
N	3		3	
L	3.40	3.60	0.134	0.142
L1	0.90	1.10	0.035	0.043
L2	0.90	1.10	0.035	0.043

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